

TRADEMARK ASSIGNMENT

Electronic Version v1.1
 Stylesheet Version v1.1

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	RELEASE BY SECURED PARTY

CONVEYING PARTY DATA

Name	Formerly	Execution Date	Entity Type
Enterprise Partners VI, LP		08/18/2005	LIMITED PARTNERSHIP: DELAWARE
KPCB Holdings, Inc. as Nominee, c/o Kleiner Perkins Caufield & Byers		08/18/2005	CORPORATION: CALIFORNIA
Dionis Trust		08/18/2005	Trust:

RECEIVING PARTY DATA

Name:	Ophthonix, Inc.
Street Address:	10455 Pacific Center Court
City:	San Diego
State/Country:	CALIFORNIA
Postal Code:	92121
Entity Type:	CORPORATION: CALIFORNIA

PROPERTY NUMBERS Total: 15

Property Type	Number	Word Mark
Serial Number:	76218642	OPHTHONIX
Serial Number:	76218638	OPHTHONIX
Serial Number:	76218640	OPHTHONIX
Serial Number:	78270043	OPHTHONIX
Serial Number:	78453706	IZON
Serial Number:	78338271	20/HAPPY IS NOT VISION OPTIMIZED
Serial Number:	78387098	VISION OPTIMIZED. NOT COMPROMISED.
Serial Number:	76218639	Z-LENS
Serial Number:	78270026	Z VIEW
Serial Number:	78387101	ZX

CH \$390.00 76218642

Serial Number:	78612317	!.ZON
Serial Number:	78615275	ME, MYSELF AND EYE
Serial Number:	78635084	!.ZON EYEGLASSES ME, MYSELF AND EYE.
Serial Number:	78648669	IZONIK
Serial Number:	78612332	Z·VIEW

CORRESPONDENCE DATA

Fax Number: (858)550-6420

Correspondence will be sent via US Mail when the fax attempt is unsuccessful.

Phone: (858) 550-6000

Email: trademarks@cooley.com

Correspondent Name: Kent M. Walker, Esq./Cooley Godward LLP

Address Line 1: 4401 Eastgate Mall

Address Line 4: San Diego, CALIFORNIA 92121-1909

NAME OF SUBMITTER:	Kent M. Walker, Esq.
Signature:	/Kent M. Walker, Esq./
Date:	11/08/2005

Total Attachments: 12

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OPHTHONIX, INC.

RELEASE OF INTELLECTUAL PROPERTY SECURITY AGREEMENT

The undersigned lenders, constituting the Majority Lenders referred to in the **INTELLECTUAL PROPERTY SECURITY AGREEMENT** dated August 18, 2005 (the "**Agreement**") by and among each of the lenders named on **Exhibit A** (the "**Lenders**") and **OPHTHONIX, INC.**, a Delaware corporation ("**Debtor**"), hereby releases and discharges on behalf of all of the Lenders, for good and valuable consideration, the entire security interest granted under the Agreement in and to Debtor's entire right, title and interest in, to and under any and all Intellectual Property now or hereafter existing, created, acquired or held by Debtor (including, without limitation, those U.S. Copyrights and Copyright applications set forth on **Exhibit B**, those U.S. Patents and Patent applications set forth on **Exhibit C** and those U.S. Trademarks and Trademark applications set forth on **Exhibit D**, all of which are incorporated herein by this reference). Capitalized terms used but not otherwise defined herein have the meanings given them in the Security Agreement (as defined in the Agreement).

IN WITNESS WHEREOF, the Majority Lenders have duly executed this release as of October 24, 2005.

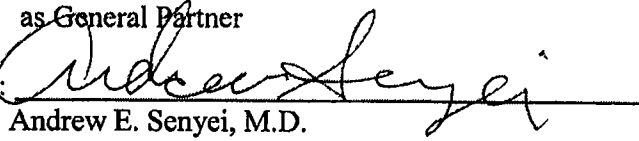
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LENDERS:

ENTERPRISE PARTNERS VI, LP

By: Enterprise Management Partners VI, LLC
as General Partner

By:



Andrew E. Senyei, M.D.
Managing Director

Address: 2223 Avenida de la Playa, Suite 300
La Jolla, CA 92037

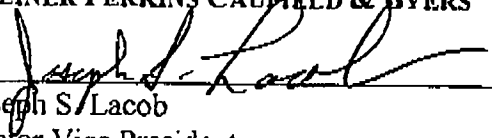
[SIGNATURE PAGE TO RELEASE OF INTELLECTUAL PROPERTY SECURITY AGREEMENT]

TRADEMARK
REEL: 003190 FRAME: 0028

LENDERS:

**KPCB HOLDINGS, INC., AS NOMINEE,
C/O KLEINER PERKINS CAUFIELD & BYERS**

By: _____


Joseph S. Lacob
Senior Vice President

Address: 2750 Sand Hill Road
Menlo Park, CA 94025

[SIGNATURE PAGE TO RELEASE OF INTELLECTUAL PROPERTY SECURITY AGREEMENT]

**TRADEMARK
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EXHIBIT A

LENDERS

Enterprise Partners VI, L.P.

KPCB Holdings, Inc., as Nominee, c/o Kleiner Perkins Caufield & Byers

Dionis Trust

EXHIBIT B

U.S. COPYRIGHTS AND COPYRIGHT APPLICATIONS

None.

EXHIBIT C

U.S. PATENTS AND PATENT APPLICATIONS

Title of Invention	Date of Filing	Publication No.	Issue No.	Application Type
Wavefront Aberrator And Method Of Manufacturing	June 4, 2001	2002/0080464	6,813,082	Regular US
Custom Eyeglass Manufacturing Method	Oct. 25, 2001	2003/0081173	6,682,195	Regular US
Eyeglass Manufacturing Method Using Variable Index Layer	Oct. 25, 2001	2003/0081172	6,712,466	Regular US
System And Method For Wavefront Measurement	Dec. 10, 2001	2003/0231298	6,781,681	Regular US
Apparatus And Method For Determining Objective Refraction Using Wavefront Sensing	Feb. 13, 2002	2003/0151721	6,761,454	Regular US
Apparatus And Method Of Correcting Higher Order Aberrations Of The Human Eye	Aug. 12, 2002	2003/0003295		Regular US (CIP)
Optical Elements And Method Of Making Them	Sept. 24, 2002	2004/0008319	6,836,371	Regular US
Apparatus And Method Of Fabricating Waveplate For Wavefront Correction Using Spatially Localized Curing Of Epoxy	Oct. 3, 2002	2003/0143391		Regular US (CIP)
Custom Eyeglass Manufacturing Method	Oct. 23, 2002	WO 03/079097		PCT
Custom Eyeglass Manufacturing Method	Oct. 23, 2002			AU Application
Custom Eyeglass Manufacturing Method	Oct. 23, 2002			EP Application
Custom Eyeglass Manufacturing Method	Oct. 23, 2002			JP Application
Eyeglass Manufacturing Method Using Variable Index Layer	Oct. 23, 2002	WO 03/035377		PCT

Eyeglass Manufacturing Method Using Variable Index Layer	Oct. 23, 2002			AU Application
Eyeglass Manufacturing Method Using Variable Index Layer	Oct. 23, 2002			EP Application
Eyeglass Manufacturing Method Using Variable Index Layer	Oct. 23, 2002			JP Application
System And Method For Wavefront Measurement	Dec. 9, 2002	2003/0214647		Regular US (CIP)
System And Method For Wavefront Measurement	Dec. 9, 2002	WO 03/050472		PCT
System And Method For Wavefront Measurement	Dec. 9, 2002			AU Application
System And Method For Wavefront Measurement	Dec. 9, 2002			EP Application
System And Method For Wavefront Measurement	Dec. 9, 2002	2005-513425		JP Application
Apparatus And Method For Determining Objective Refraction Using Wavefront Sensing	Feb. 13, 2003	WO 03/068059		PCT
Apparatus And Method For Objective Characterization Of Vision Based On Wavefront Sensing	Feb. 13, 2003			AU Application
Apparatus And Method For Objective Characterization Of Vision Based On Wavefront Sensing	Feb. 13, 2003			EP Application
Apparatus And Method For Objective Characterization Of Vision Based On Wavefront Sensing	Feb. 13, 2003			JP Application
Optical Elements And Method Of Making Them	June 24, 2003	WO 2004/008189		PCT
Optical Elements And Method Of Making Them	June 24, 2003			AU Application
Optical Elements And Method Of Making Them	June 24, 2003			EP Application
Optical Elements And Method Of Making Them	June 24, 2003			IL Application

Optical Elements And Method Of Making Them	June 24, 2003			JP Application
Apparatus And Method Of Correcting Higher Order Aberrations Of The Human Eye	July 30, 2003	WO 2004/015481		PCT
Apparatus And Method Of Correcting Higher Order Aberrations Of The Human Eye	July 30, 2003			AU Application
Apparatus And Method Of Correcting Higher Order Aberrations Of The Human Eye	July 30, 2003			EP Application
Apparatus And Method Of Correcting Higher Order Aberrations Of The Human Eye	July 30, 2003			JP Application
Apparatus And Method For Determining Objective Refraction Using Wavefront Sensing	Sept. 2, 2003			Regular US
Apparatus And Method Of Fabricating Waveplate For Wavefront Correction Using Spatially Localized Curing Of Resin Mixtures	Sept. 4, 2003	WO 2004/034095		PCT
Apparatus And Method Of Fabricating Waveplate For Wavefront Correction Using Spatially Localized Curing Of Resin Mixtures	Sept. 4, 2003			AU Application
Apparatus And Method Of Fabricating Waveplate For Wavefront Correction Using Spatially Localized Curing Of Resin Mixtures ²	Sept. 4, 2003			EP Application
Apparatus And Method Of Fabricating Waveplate For Wavefront Correction Using Spatially Localized Curing Of Resin Mixtures	Sept. 4, 2003			IL Application
Apparatus And Method Of Fabricating Waveplate For Wavefront Correction Using Spatially Localized Curing Of Resin Mixtures	Sept. 4, 2003	2004-543274		JP Application
Apparatus And Method Of Determining Objective Refraction Using Wavefront Sensing	Dec. 11, 2003			Regular US
Custom Eyeglass Manufacturing Method	Jan. 13, 2004			Regular US

Eyeglass Manufacturing Method Using Variable Index Layer	Feb. 6, 2004	2004/0160574	6,840,619	Regular US
Apparatus And Method For Curing Of UV-Protected UV Curable Monomers	May 18, 2004			Regular US
Apparatus And Method For Curing Of UV-Protected UV Curable Monomers	May 19, 2004	WO 2004/106990		PCT
Method Of Fabricating Wavefront Sensor With Surface Boundary Scanning	May 21, 2004			Regular US (CIP)
Apparatus And Method For Determining Objective Refraction Using Wavefront Sensing	July 12, 2004	2005/0030477		Regular US
Optical Elements And Method Of Making Them	Sept. 7, 2004	2005/0046957		Regular US
System For Manufacturing an Optical Lens	Sept. 7, 2004	2005/0105048		Regular US
Stabilized Photopolymer Materials And Methods	Sept. 7, 2004			Regular US
Method of Manufacturing an Optical Lens	Sept. 7, 2004	2005/0104240		Regular US
Method For Stabilizing Refractive Index Profiles Using Polymer Mixtures	Sept. 7, 2004			Regular US
Eyeglass Dispensing Method	Sept. 7, 2004	2005/0105043		Regular US
Eyeglass Manufacturing Method Using Variable Index Layer	Sept. 20, 2004	2005/0036106		Regular US
Wavefront Aberrator And Method Of Manufacturing	Sept. 20, 2004	2005/0052747		Regular US
Optical Elements And Method Of Making Them	Oct. 5, 2004	2005/0057815		Regular US
Optical Elements And Method Of Making Them	Oct. 5, 2004	2005/0064105		Regular US
Ophthalmic Diagnostic Instrument	Oct. 22, 2004			Regular US
Lensometer and Wavefront Sensor and Methods of Measuring Aberrations	Oct. 22, 2004	2005/0105044		Regular US

System for Manufacturing an Optical Element	Oct. 29, 2004	WO 2005/050290		PCT
Ophthalmic Diagnostic Instrument	Oct. 29, 2004	WO 2005/048829		PCT
Lensometer and Wavefront Sensor and Methods of Measuring Aberrations	Oct. 29, 2004	WO 2005/052538		PCT
Eyeglass Manufacturing Method	Oct. 29, 2004	WO 2005/050289		PCT
Eyeglass Manufacturing Method Using Variable Index Layer	Dec. 2, 2004	2005/0083481		Regular US
Custom Eyeglass Manufacturing Method	Dec. 14, 2004			PCT
System And Method For Analyzing Wavefront Aberrations	Feb. 22, 2005			Regular US
System And Method For Analyzing Wavefront Aberrations	Feb. 22, 2005			PCT
Apparatus And Method For Curing Of UV-Protected UV Curable Monomers	May 18, 2005			Regular US
Apparatus And Method For Determining Sphere And Cylinder Components Of Subjective Refraction Using Objective Wavefront Measurement	May 21, 2005			Regular US

EXHIBIT D

U.S. TRADEMARKS AND TRADEMARK APPLICATIONS

Title of Trademark & Class	Date of Filing	Serial No.	Register No.	Country
OPHTHONIX (Class 9)	3/2/2001	76/218,642		United States
OPHTHONIX (Class 10)	3/2/2001	76/218,638	2,925,566	United States
OPHTHONIX (Class 40)	3/2/2001	76/218,640		United States
OPHTHONIX	9/29/2004	1232818		Canada
OPHTHONIX & DESIGN (Class 7, 9, 10, 40)	7/2/2003	78/270,043		United States
OPHTHONIX & DESIGN (Class 7, 9, 10, 40)	12/24/2003	3595501	3595501	Europe
IZON (Class 9, 10)	7/20/2004	78/453,706		United States
IZON	12/22/2004	1242459		Canada
IZON (Class 9, 10)	1/10/2005	004234027		Europe
20/HAPPY IS NOT VISION OPTIMIZED (Class 7, 9, 10, 40)	12/9/2003	78/338,271		United States
20/HAPPY IS NOT VISION OPTIMIZED (Class 7, 9, 10, 40)	5/21/2004	003847449		Europe
VISION OPTIMIZED. NOT COMPROMISED (Class 7, 9, 10, 40, 44)	3/18/2004	78/387,098		United States
VISION OPTIMIZED. NOT COMPROMISED	9/16/2004	1231006		Canada
VISION OPTIMIZED. NOT COMPROMISED (Class 7, 9, 10, 40,	9/17/2004	004032157		Europe

44)				
Z-LENS (Class 9)	3/2/2001	76/218,639		United States
Z VIEW (Class 7, 9, 10, 40)	7/2/2003	78/270,026		United States
Z VIEW	9/29/2004	1232819		Canada
Z VIEW (Class 7, 9, 10, 40)	12/24/2003	3595345		Europe
ZX (Class 7, 9, 10, 40, 44)	3/18/2004	78/387,101		United States
IZON (STYLIZED) (Class 9, 10)	4/19/2005	78/612,317		United States
Z VIEW (STYLIZED) (Class 7, 9)	4/19/2005	78/615,332		United States
ME, MYSELF, AND EYE (Class 9, 10)	4/22/2005	78/615,275		United States
IZON ME, MYSELF AND EYE & EYE DESIGN (Class 9, 10)	5/23/2005	78/635,084		United States
IZONIK (Class 1)	6/10/2005	78/648,669		United States

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